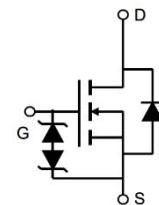
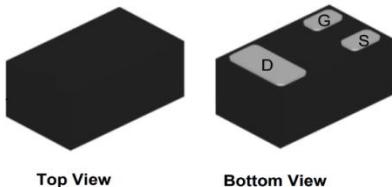
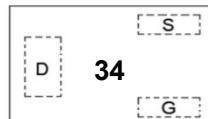


N-Channel Enhancement Mode MOSFET**Features**

- Advanced Trench Process Technology
- Low Threshold Voltage
- Fast Switching Speed
- Halogen-Free & Lead-Free
- ESD Protected up to 2KV (HBM)

**Application**

- Load Switch for Portable Devices
- Voltage controlled small signal switch

DFN1006-3L
Marking: 34**Absolute Maximum Ratings (at $T_a = 25^\circ\text{C}$ unless otherwise specified)**

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	0.75	A
Peak Drain Current, Pulsed ¹⁾	I_{DM}	1.8	A
Power Dissipation ²⁾	P_{tot}	0.7	W
Operating Junction	T_J	-55~150	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55~150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Max.	Unit
Thermal Resistance from Junction to Ambient ²⁾	$R_{\theta JA}$	175	$^\circ\text{C}/\text{W}$

Note:

1) Pulse width $\leq 100\mu\text{s}$, duty cycle $\leq 1\%$, limite by T_{Jmax} .

2) Device mounted on FR-4 substrate PC board, 2ozcopper, with 1-inch square copper plate in still air.

Characteristics at $T_a = 25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit
STATIC PARAMETERS					
Drain-Source Breakdown Voltage at $I_D = 250 \mu\text{A}$	BV_{DSS}	20			V
Drain-Source Leakage Current at $V_{\text{DS}} = 20 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$	I_{DSS}			1.0	μA
Gate Leakage Current at $V_{\text{GS}} = \pm 10 \text{ V}$	I_{GSS}			± 10	μA
Gate-Source Threshold Voltage at $V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250 \mu\text{A}$	$V_{\text{GS}(\text{th})}$	0.35	0.7	1.1	V
Drain-Source On-State Resistance at $V_{\text{GS}} = 4.5 \text{ V}$, $I_D = 0.65 \text{ A}$ at $V_{\text{GS}} = 2.5 \text{ V}$, $I_D = 0.45 \text{ A}$	$R_{\text{DS}(\text{on})}$		250 300	500 700	$\text{m}\Omega$
DYNAMIC PARAMETERS					
Forward Transconductance at $V_{\text{DS}} = 5 \text{ V}$, $I_D = 0.15 \text{ A}$	g_{fs}	15			mS
Input Capacitance at $V_{\text{GS}} = 0 \text{ V}$, $V_{\text{DS}} = 16 \text{ V}$, $f = 1 \text{ MHz}$	C_{iss}		79		pF
Output Capacitance at $V_{\text{GS}} = 0 \text{ V}$, $V_{\text{DS}} = 16 \text{ V}$, $f = 1 \text{ MHz}$	C_{oss}		13		pF
Reverse Transfer Capacitance at $V_{\text{GS}} = 0 \text{ V}$, $V_{\text{DS}} = 16 \text{ V}$, $f = 1 \text{ MHz}$	C_{rss}		9		pF
Gate charge total at $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.65 \text{ A}$, $V_{\text{GS}} = 4.5 \text{ V}$	Q_g		1.24		nC
Gate to Source Charge at $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.65 \text{ A}$, $V_{\text{GS}} = 4.5 \text{ V}$	Q_{gs}		0.37		nC
Gate to Drain Charge at $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.65 \text{ A}$, $V_{\text{GS}} = 4.5 \text{ V}$	Q_{gd}		0.27		nC
Turn-On Delay Time at $V_{\text{GS}} = 4.5 \text{ V}$, $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.5 \text{ A}$, $R_g = 10 \Omega$	$t_{\text{d}(\text{on})}$		6.7		ns
Turn-On Rise Time at $V_{\text{GS}} = 4.5 \text{ V}$, $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.5 \text{ A}$, $R_g = 10 \Omega$	t_r		4.8		ns
Turn-Off Delay Time at $V_{\text{GS}} = 4.5 \text{ V}$, $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.5 \text{ A}$, $R_g = 10 \Omega$	$t_{\text{d}(\text{off})}$		17.3		ns
Turn-Off Fall Time at $V_{\text{GS}} = 4.5 \text{ V}$, $V_{\text{DS}} = 10 \text{ V}$, $I_D = 0.5 \text{ A}$, $R_g = 10 \Omega$	t_f		7.4		ns
Body-Diode PARAMETERS					
Drain-Source Diode Forward Voltage at $I_s = 0.15 \text{ A}$, $V_{\text{GS}} = 0 \text{ V}$	V_{SD}			1.2	V
Body Diode Reverse Recovery Time at $I_F = 5.6 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$	t_{rr}		14		ns
Body Diode Reverse Recovery Charge at $I_F = 5.6 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$	Q_{rr}		0.4		nC

Electrical Characteristics Curves

Fig. 1 - Output Characteristics

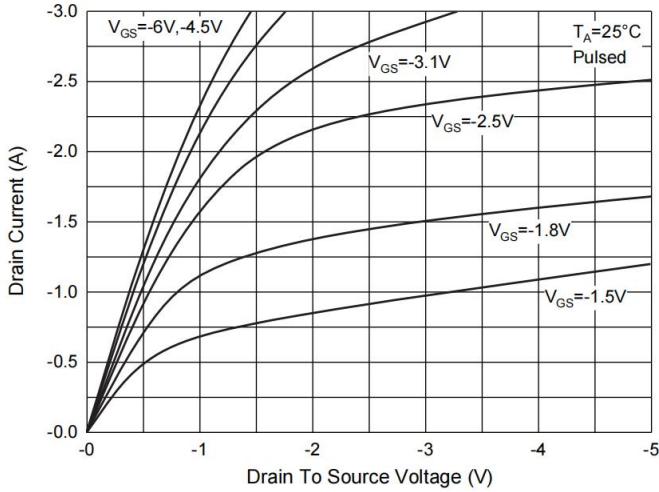


Fig. 3 - $R_{DS(\text{ON})} - I_D$

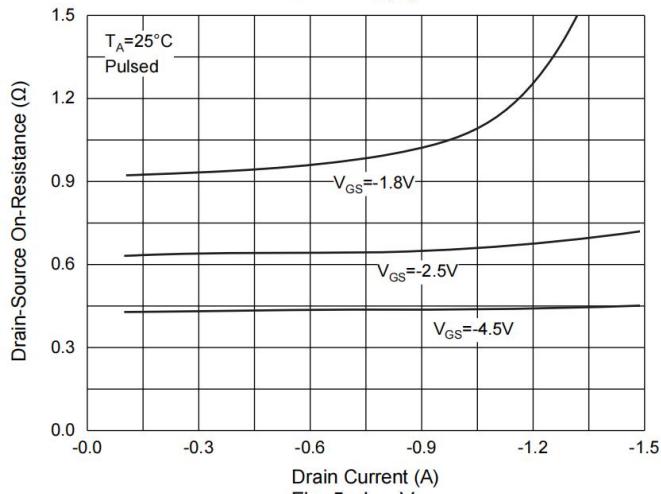


Fig. 5 - $I_S - V_{SD}$

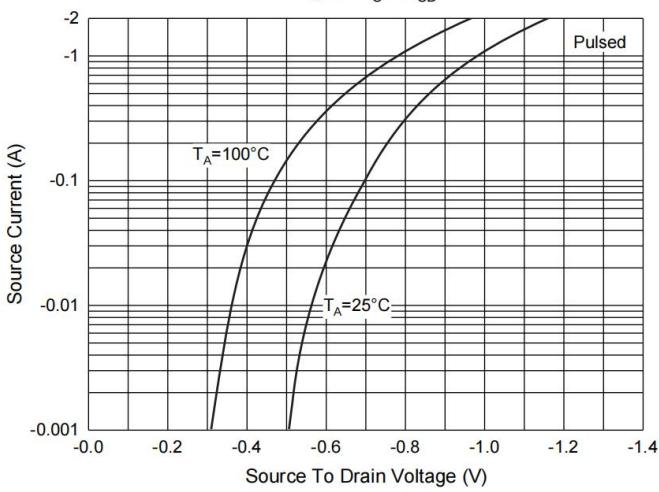


Fig. 2 - Transfer Characteristics

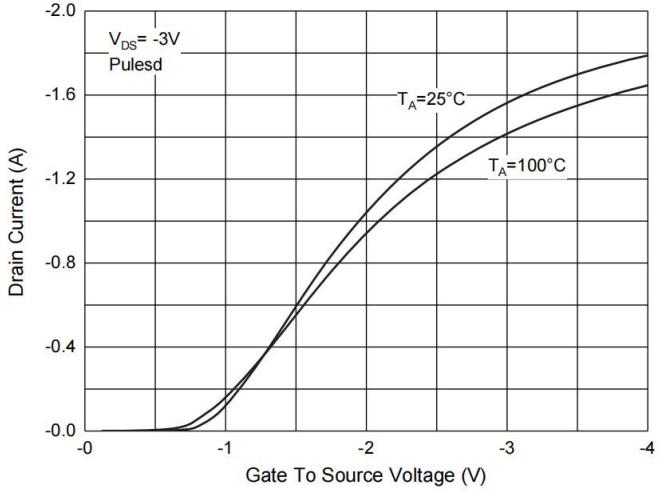


Fig. 4 - $R_{DS(\text{ON})} - V_{GS}$

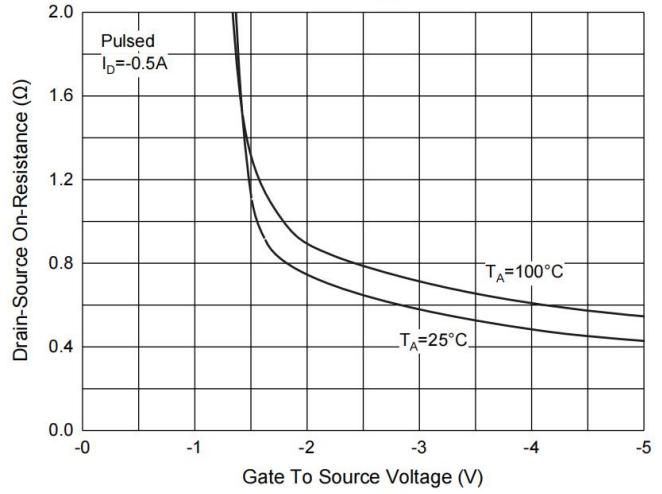
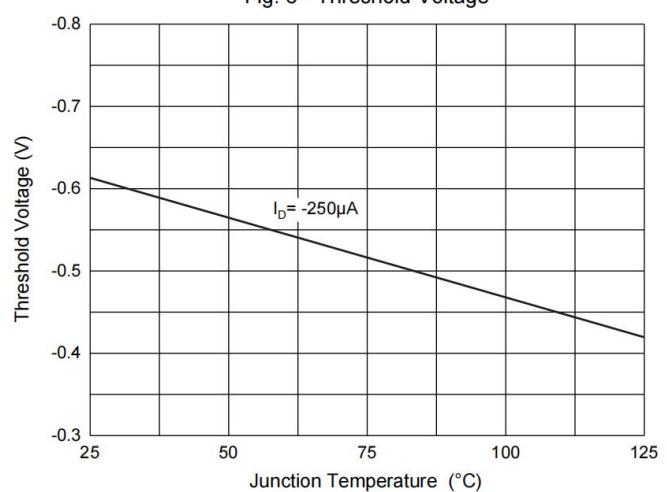


Fig. 6 - Threshold Voltage



Test Circuits

Fig.1-1 Switching times test circuit

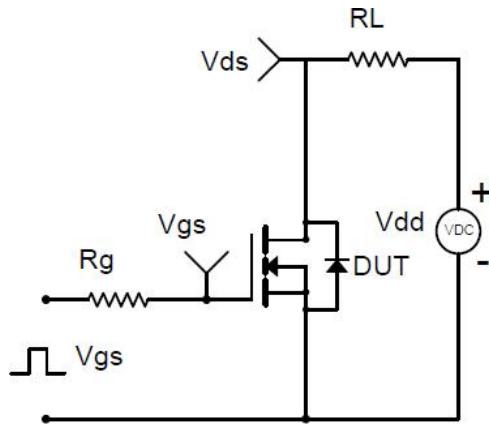


Fig.1-2 Switching Waveform

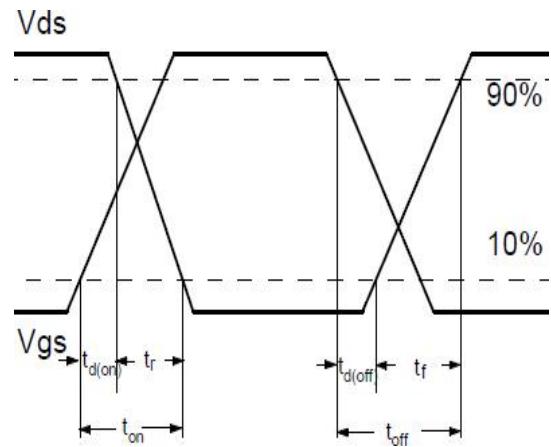


Fig.2-1 Gate charge test circuit

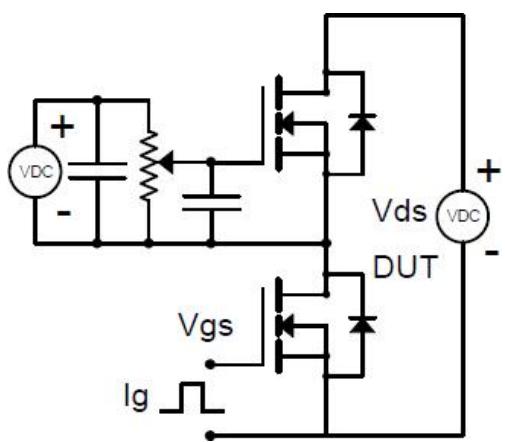


Fig.2-2 Gate charge waveform

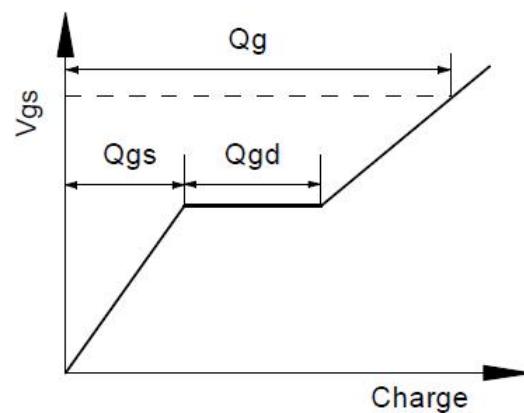


Fig.3-1 Avalanche test circuit

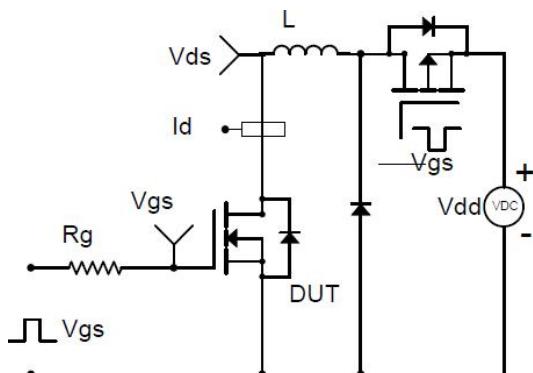
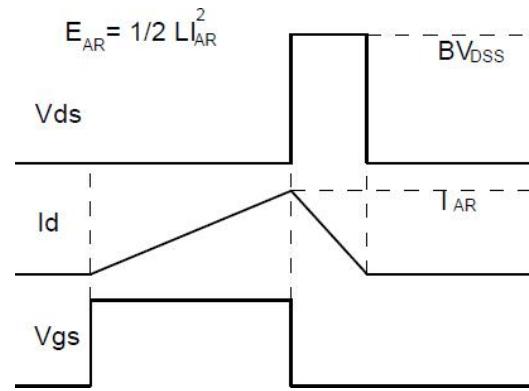
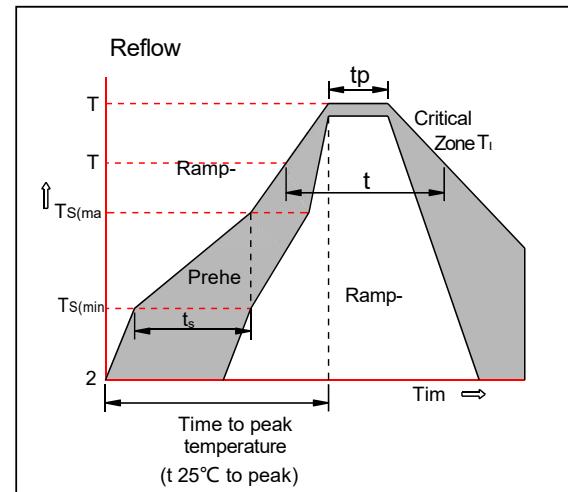


Fig.3-2 Avalanche waveform



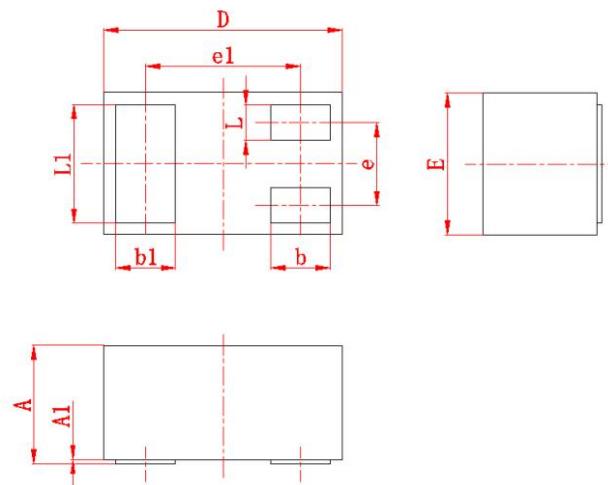
Soldering parameters

Reflow Condition		Pb-Free assembly (see as bellow)
Pre Heat	-Temperature Min ($T_{s(\min)}$)	+150°C
	-Temperature Max($T_{s(\max)}$)	+200°C
	-Time (Min to Max) (ts)	60-180 secs.
Average ramp up rate (Liquid us Temp (T_L) to peak)		3°C/sec. Max
$T_{s(\max)}$ to T_L - Ramp-up Rate		3°C/sec. Max
Reflow	-Temperature(T_L)(Liquid us)	+217°C
	-Temperature(t_L)	60-150 secs.
Peak Temp (T_p)		+260(+0/-5)°C
Time within 5°C of actual Peak Temp (t_p)		30 secs. Max
Ramp-down Rate		6°C/sec. Max
Time 25°C to Peak Temp (T_p)		8 min. Max
Do not exceed		+260°C



Package Outline Dimensions (Units: mm)

DFN1006-3L



Symbol	Dimensions		Symbol	Dimensions		Symbol	Dimensions	
	Min	Max		Min	Max		Min	Max
A	0.4	0.5	e	(0.35)		L	0.1	0.2
A1	0	0.05	e1	(0.65)		L1	0.45	0.55
D	0.9	1.1	b	0.2	0.3			
E	0.55	0.65	b1	0.2	0.3			